



# 제25회 한국반도체학술대회

The 25<sup>th</sup> Korean Conference on Semiconductors

2018년 2월 5일(월)-7일(수), 강원도 하이원리조트 컨벤션 호텔

2018년 2월 7일(수), 10:45-12:15

Room B (태백II+III, 5층)

## Special Session

### [WB2-SS] Special Session: IoT I

|                         |   |
|-------------------------|---|
| WB2-SS-1<br>10:45-11:00 | <b>IOT/ICT 응용 기술을 활용한 SCS(Smart Control System) 개발</b><br>지문영<br><i>Department of PKG Technology Development, SK Hynix</i>  |
| WB2-SS-2<br>11:00-11:15 | <b>Reliability Modeling of DRAM Storage Capacitors</b><br>Seongun Shin <sup>1</sup> , Gyuhan Yoon <sup>1</sup> , Seon Young Cha <sup>2</sup> , Seon Soon Kim <sup>2</sup> , Kwang Ho Ahn <sup>2</sup> , Woo Young Chung <sup>2</sup> , Se Hyun Kim <sup>2</sup> , and Woo Young Choi <sup>1</sup><br><i><sup>1</sup>Department of Electronic Engineering, Sogang University, <sup>2</sup>DRAM Business Unit, SK Hynix</i> |
| WB2-SS-3<br>11:15-11:30 | <b>High-Responsivity Deep-Ultraviolet-Selective Photodetector Using Amorphous GaOx Thin Films Grown by Atomic Layer Deposition</b><br>Kang Min Lee, Seung Hyun Lee, and Sang Woon Lee<br><i>Department of Energy Systems Research and Department of Physics, Ajou University</i>  |
| WB2-SS-4<br>11:30-11:45 | <b>전력 IOT 용 고효율 자기 하베스팅 다중 센서</b><br>Towoo Lim, Sol Hwang, Changhun Hong, and Youngmin Kim<br><i>School of Electrical Eng., Hongik University</i>   |
| WB2-SS-5<br>11:45-12:00 | <b>Innovative Approaches to Transient Low-Current Measurement for IoT</b><br>Jeong-Tae Kim<br><i>Keysight Technologies Korea</i>  |
| WB2-SS-6<br>12:00-12:15 | <b>Improvement of Sensing Margin and Reset Switching Fail of ReRAM</b><br>Woo Young Park, WonKi Ju, JooYoung Moon, YoungSeok Ko, BoMi Lee, Jae Yeon Lee, Tae Jung Ha, Yong Taek Park, KyungWan Kim, Soo Gil Kim, and ByoungKi Lee<br><i>ReRAM team, R&amp;D Division, SK Hynix Semiconductor Inc.</i>   |